NOTICE OF REVISION (NOR) This revision described below has been authorized for the document listed.	1. DATE (YYMMDD) 94-04-20	Form Approved OMB No. 0704-0188
Public reporting burden for this collection is estimated to average 2 hours per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden, to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports, 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302, and to the Office of Management and Budget, Paperwork Reduction Project (0704-0188), Washington, DC 20503. PLEASE DO NOT RETURN YOUR COMPLETED FORM TO EITHER OF THESE ADDRESSED. RETURN COMPLETED FORM TO THE GOVERNMENT ISSUING CONTRACTING OFFICER FOR THE CONTRACT/ PROCURING ACTIVITY NUMBER LISTED IN ITEM 2 OF THIS FORM.		2. PROCURING ACTIVITY NO. 3. DODAAC

4. ORIGINATOR	b. ADDRESS (Street, City, State, Zip Code)	5. CAGE CODE 67268	6. NOR NO. 5962-R151-94
a. TYPED NAME (First, Middle Initial, Last)	Defense Electronics Supply Center 1507 Wilmington Pike Dayton, OH 45444-5765	7. CAGE CODE 67268	8. DOCUMENT NO. **79015**

9. TITLE OF DOCUMENT	10. REVISION LETTER		11. ECP NO.
MICROCIRCUIT, DIGITAL, CMOS, DIFFERENTIAL 4-CHANNEL ANALOG, MULTIPLEXER/DEMULTIPLEXER, MONOLITHIC SILICON	a. CURRENT F	b. NEW G	N/A

12. CONFIGURATION ITEM (OR SYSTEM) TO WHICH ECP APPLIES
All

13. DESCRIPTION OF REVISION

Sheet 1: Revisions ltr column; add "G".
Revisions description column; add "Changes in accordance with NOR 5962-R151-94".
Revisions date column; add "94-04-20".
Revision level block; delete "F" and substitute "G".
Rev status of sheets; For sheets 1, 6, 7, and 8 delete "F" and substitute "G".

Sheet 6: TABLE I, Propagation delay time, signal input to output, t_{PHL1}, t_{PLH1}; conditions column add "5/".
TABLE I, Propagation delay time, signal input to output, t_{PHL1}, t_{PLH1}; V_{DD} = 10 V, device type 03, subgroup 9 add "3/".
TABLE I, Propagation delay time, signal input to output, t_{PHL1}, t_{PLH1}; V_{DD} = 15 V, device type 03, subgroup 9 add "3/".
Revision level block; delete "F" and substitute "G".

Sheet 7: TABLE I, Propagation delay time, address to signal output, t_{PHL2}, t_{PLH2}; V_{DD} = 10 V, device type 03, subgroup 9 add "3/".
TABLE I, Propagation delay time, address to signal output, t_{PHL2}, t_{PLH2}; V_{DD} = 15 V, device type 03, subgroup 9 add "3/".
TABLE I, Propagation delay time, inhibit to signal out, (channel turning on) t_{PZH}, t_{PZL}; V_{DD} = 10 V, device type 03, subgroup 9 add "3/".
Revision level block; delete "F" and substitute "G".

CONTINUED ON FOLLOWING PAGE:

14. THIS SECTION FOR GOVERNMENT USE ONLY

a. (X one)		
	X	(1) Existing document supplemented by the NOR may be used in manufacture.
		(2) Revised document must be received before manufacturer may incorporate this change.
		(3) Custodian of master document shall make above revision and furnish revised document.

b. ACTIVITY AUTHORIZED TO APPROVE CHANGE FOR GOVERNMENT	c. TYPED NAME (First, Middle Initial, Last)
ELDC	Monica L. Poelking

d. TITLE	e. SIGNATURE	f. DATE SIGNED (YYMMDD)
Chief, Custom Microelectronics	Monica L. Poelking	94-04-20

15a. ACTIVITY ACCOMPLISHING REVISION	b. REVISION COMPLETED (Signature)	c. DATE SIGNED (YYMMDD)
ELDC	Larry T. Gauder	94-04-20

13. DESCRIPTION OF REVISION - CONTINUED

Sheet 8: TABLE I, Propagation delay time, inhibit to signal out (channel turning on), t_{PZH}, t_{PZL}; V_{DD} = 15 V, device type 03 subgroup 9 add "3/".
TABLE I, t_{PZH}, t_{PZL}; V_{DD} = 15 V, units column add "ns".
TABLE I, Propagation delay time, inhibit to signal out (channel tuning off), t_{PHZ}, t_{PLZ}; V_{DD} = 5 V, conditions column add "5/".
TABLE I, t_{PHZ}, t_{PLZ}; V_{DD} = 5 V, units column add "ns".
TABLE I, Propagation delay time, inhibit to signal out (channel turning off), t_{PHZ}, t_{PLZ}; V_{DD} = 10 V, device type 03 subgroup 9 add "3/".
Revision level block; delete "F" and substitute "G".

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
B	Remove one vendor - FSCM - 04713. Editorial changes throughout.	84-03-22	Monica Poelking
C	Table I: Remove minimum ac limits and change t_{PHL} and t_{PLH} limits.	84-05-14	Monica Poelking
D	Add vendor CAGE 34371. Remove vendor CAGE 07263. Technical changes in 1.3, 1.4, table I. Change to military drawing format. Change drawing CAGE code to 67268. Add device type 02. Editorial changes throughout.	90-03-26	Monica Poelking
E	IAW NOR 5962-R107-92.	92-01-10	Monica Poelking
F	Redrawn with changes. Add device type 03. Technical changes to table I. Updated boilerplate. Editorial changes throughout.	94-01-13	Monica Poelking

THE ORIGINAL FIRST PAGE OF THIS DRAWING HAS BEEN REPLACED.

CURRENT CAGE CODE 67268

REV																			
SHEET																			
REV																			
SHEET																			

REV STATUS OF SHEETS																
REV	F	F	F	F	F	F	F	F	F	F	F	F	F	F	F	F
SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13	14		

PMIC N/A

STANDARDIZED MILITARY DRAWING

THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE

AMSC N/A

PREPARED BY
Marcia B. Kelleher

CHECKED BY
Thomas J. Ricciuti

APPROVED BY
Monica L. Poelking

DRAWING APPROVAL DATE
79-05-15

REVISION LEVEL
F

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO 45444

MICROCIRCUIT, DIGITAL, CMOS, DIFFERENTIAL 4-CHANNEL ANALOG, MULTIPLEXER/DEMULTIPLEXER, MONOLITHIC SILICON

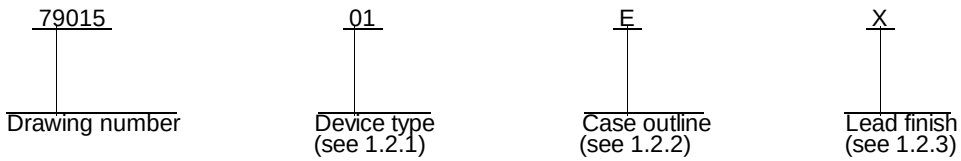
SIZE	CAGE CODE	
A	**14933**	**79015**

SHEET 1 OF 14

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:



1.2.1 Device type(s). The device type(s) shall identify the circuit function as follows:

Device type	Generic number	Circuit
01	4052B	Differential 4-channel analog multiplexer/demultiplexer
02	4052B	Differential 4-channel analog multiplexer/demultiplexer
03	14052B	Differential 4-channel analog multiplexer/demultiplexer

1.2.2 Case outline(s). The case outline(s) shall be as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	Terminals	Package style
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line package
F	GDFP2-F16 or CDFP3-F16	16	Flat package

1.2.3 Lead finish. The lead finish shall be as specified in MIL-M-38510. Finish letter "X" shall not be marked on the microcircuit or its packaging. The "X" designation is for use in specifications when lead finishes A, B, and C are considered acceptable and interchangeable without preference.

1.3 Absolute maximum ratings.

Supply voltage range (V_{DD}):	
Device types 01 and 03	-0.5 V dc to +18 V dc
Device type 02	-0.5 V dc to +20 V dc
Input voltage range	-0.5 V dc to V_{DD} + 0.5 V dc
DC input current	±10 mA
Storage temperature range	-65°C to +150°C
Maximum power dissipation (P_D) 1/	500 mW dc
Lead temperature (soldering, 10 seconds)	+300°C
Thermal resistance, junction-to-case (Θ_{JC})	See MIL-STD-1835
Junction temperature (T_J)	+175°C

1.4 Recommended operating conditions.

Supply voltage range (V_{CC}):	
Device types 01 and 03	+3.0 V dc to +15 V dc
Device type 02	+3.0 V dc to +18 V dc
Case operating temperature range (T_C)	-55°C to +125°C

1/ For T_C = +100°C to +125°C, derate linearly at 12 mW/°C to 200 mW.

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARDS

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.
MIL-STD-1835 - Microcircuit Case Outlines.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standards and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table. The truth table shall be as specified on figure 2.

3.2.4 Logic diagram. The logic diagram shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ unless otherwise specified	Device types	GroupA subgroups	Limits Min	Limits Max	Unit
Quiescent supply current	I_{DD}	V_{DD} = 5 V, 1/ V_{IN} = 0.0 V or V_{DD}	All	1, 3		5	µA
				2		150	
		V_{DD} = 10 V, 1/ V_{IN} = 0.0 V or V_{DD}	All	1, 3		10	
				2		300	
		V_{DD} = 15 V, 1/ V_{IN} = 0.0 V or V_{DD}	All	1, 3		20	
				2		600	
		V_{DD} = 20 V, 2/ V_{IN} = 0.0 V or V_{DD}	02	1, 3		100	
				2		3000	
Low level input voltage	V_{IL}	V_{DD} = 5 V, $V_{EE} = V_{SS}$ R_L = 1 kΩ to V_{SS} I_{IS} < 2 µA on all off channels	All	1, 2, 3		1.5	V
		V_{DD} = 10 V, R_L = 1 kΩ to V_{SS} 3/ I_{IS} < 2 µA on all off channels	All	1, 2, 3		3.0	
		V_{DD} = 15 V, R_L = 1 kΩ to V_{SS} I_{IS} < 2 µA on all off channels	All	1, 2, 3		4.0	
High level input voltage	V_{IH}	V_{DD} = 5 V, R_L = 1 kΩ to V_{SS} I_{IS} < 2 µA on all off channels	All	1, 2, 3	3.5		V
		V_{DD} = 10 V, 3/ R_L = 1 kΩ to V_{SS} I_{IS} < 2 µA on all off channels	All	1, 2, 3	7.0		
		V_{DD} = 15 V, R_L = 1 kΩ to V_{SS} I_{IS} < 2 µA on all off channels	All	1, 2, 3	11.0		

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ unless otherwise specified	Device types	Group A subgroups	Limits Min	Limits Max	Unit
Input current	I_{IN}	V_{DD} = 15 V, V_{IN} = 0.0 V or V_{DD}	01, 03	1, 3		±0.1	µA
				2		±1.0	
		V_{DD} = 20 V, V_{IN} = 0.0 V or V_{DD} 2/	02	1, 3		±0.1	
				2		±1.0	
Input capacitance	C_{IN}	V_{IN} = 0 V, T_C = +25°C, See 4.3.1c	All	4		7.5	pF
Functional test		See 4.3.1d	All	7			
On-state resistance	R_{ON}	V_{DD} = 5 V	01	1 2 3		2500 3500 2000	Ω
			02 03	1 2 3		1050 1300 800	
		V_{DD} = 10 V	01	1 2 3		500 660 340	
			02	1 2 3		400 550 310	
			03	1 2 3		500 550 400	
		V_{DD} = 15 V	01,	1 2 3		280 400 220	
			02	1 2 3		240 320 200	
			03	1 2 3		280 320 220	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ unless otherwise specified		Device types	Group A subgroups	Limits Min	Limits Max	Unit
Propagation delay time, signal input to output	t_{PHL1}, t_{PLH1}	R_L = 200 kΩ, C_L = 50 pF $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 5 V	01	9		60	ns
					10, 11		90	
				02 4/	9	1.5	60	
					10, 11	1.5	90	
				03	9		75	
					3/ 10, 11		112.5	
			V_{DD} = 10 V	01,03	9		35	
					3/ 10, 11		50	
				02 4/	9	1.5	30	
					10, 11	1.5	45	
			V_{DD} = 15 V	01 3/	9		25	
					10, 11		35	
				02 4/	9	1.5	20	
					10, 11	1.5	30	
				03	9		25	
					3/ 10, 11		37.5	
Propagation delay time, address to signal output	t_{PHL2}, t_{PLH2}	R_L = 10 KΩ C_L = 50 pF $t_f = t_r$ = 20 ns See figure 4	V_{DD} = 5 V	01,	9		1000	
					10, 11		1400	
				02	9	1.5	720	
					10, 11	1.5	1080	
				03	9		650	
					3/ 10, 11		975	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ unless otherwise specified		Device types	Group A subgroups	Limits Min	Limits Max	Unit
Propagation delay time, address to signal output	t_{PHL2}, t_{PLH2}	R_L = 10 kΩ C_L = 50 pF $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 10 V	01,	9		360	ns
					10, 11		505	
				02 3/	9	1.5	320	
					10, 11	1.5	480	
				03	9		260	
					3/ 10, 11		390	
Propagation delay time, address to to signal output	t_{PHL2}, t_{PLH2}		V_{DD} = 15 V	01,3/	9		240	
					10, 11		335	
				02 3/	9	1.5	240	
					10, 11	1.5	360	
				03	9		180	
					3/ 10, 11		270	
Propagation delay time, inhibit to signal out (Channel turning ON)	t_{PZH}, t_{PZL}	R_L = 10 kΩ, C_L = 50 pF, $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 5 V	01,	9		1200	
					10, 11		1800	
				02	9	1.5	720	
					10, 11	1.5	1080	
				03	9		600	
					3/ 10, 11		900	
			V_{DD} = 10 V	01,	9		450	
					10, 11		630	
				02 3/	9	1.5	320	
					10, 11	1.5	480	
				03	9		310	
					3/ 10, 11		465	

See footnotes at end of table.

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions $-55°C \le T_C \le +125°C$ unless otherwise specified		Device types	Group A subgroups	Limits Min	Limits Max	Unit
Propagation delay time, inhibit to signal out (channel turning on)	t_{PZH}, t_{PZL}	R_L = 10kΩ C_L = 50 pF $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 15 V	01,3/	9		320	ns
					10, 11		450	
				02 3/	9	1.5	240	
					10, 11	1.5	360	
				03	9		250	
					3/ 10, 11		375	
Propagation delay time, inhibit to signal out (Channel turning OFF)	t_{PHZ}, t_{PLZ}	R_L = 1kΩ C_L = 50 pF $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 5 V	01	9		420	ns
					10, 11		630	
				02	9	1.5	450	
					10, 11	1.5	675	
				03	9		600	
					3/ 10, 11		900	
Propagation delay time, inhibit to signal out (Channel turning OFF)	t_{PHZ}, t_{PLZ}	R_L = 1 kΩ, C_L = 50 pF, $t_r = t_f$ = 20 ns See figure 4	V_{DD} = 10 V 5/	01	9		200	ns
					10, 11		280	
				02 3/	9	1.5	210	
					10, 11	1.5	315	
				03	9		310	
					3/ 10, 11		465	
			V_{DD} = 15 V 5/	01 3/	9		150	
					10, 11		210	
				02 3/	9	1.5	160	
					10, 11	1.5	240	
				03 3/	9		250	
					3/ 10, 11		375	

1/ Guaranteed, if not tested, to the specified limits, for device type 02.
2/ This test is performed at V_{DD} = 18 V at -55°C.
3/ Guaranteed, if not tested, to the specified limits.
4/ Guaranteed by R_{ON} test as specified in table I.
5/ Device type 03 R_L = 10 KΩ.

Device types	01, 02, and 03
Case outlines	E and F
Terminal number	Terminal symbol
1	Y0
2	Y2
3	Y
4	Y3
5	Y1
6	INHIBIT
7	V_{EE}
8	V_{SS}
9	B
10	A
11	X3
12	X0
13	X
14	X1
15	X2
16	V_{DD}

FIGURE 1. Terminal connections.

Devices types 01, 02, and 03

Inhibit	Select		On switches	
	B	A		
L	L	L	Y0	X0
L	L	H	Y1	X1
L	H	L	Y2	X2
L	H	H	Y3	X3
H	X	X	None	None

H = High voltage level
L = Low voltage level
X = Irrelevant

FIGURE 2. Truth table.

Device types 01, 02 and 03

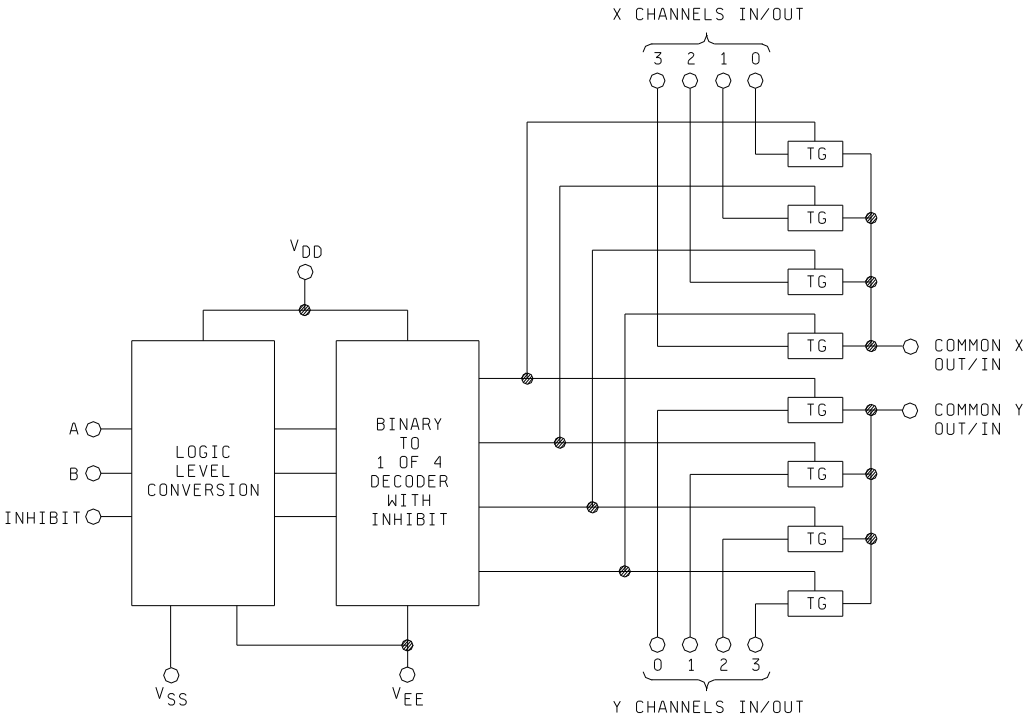


FIGURE 3. Logic diagram.

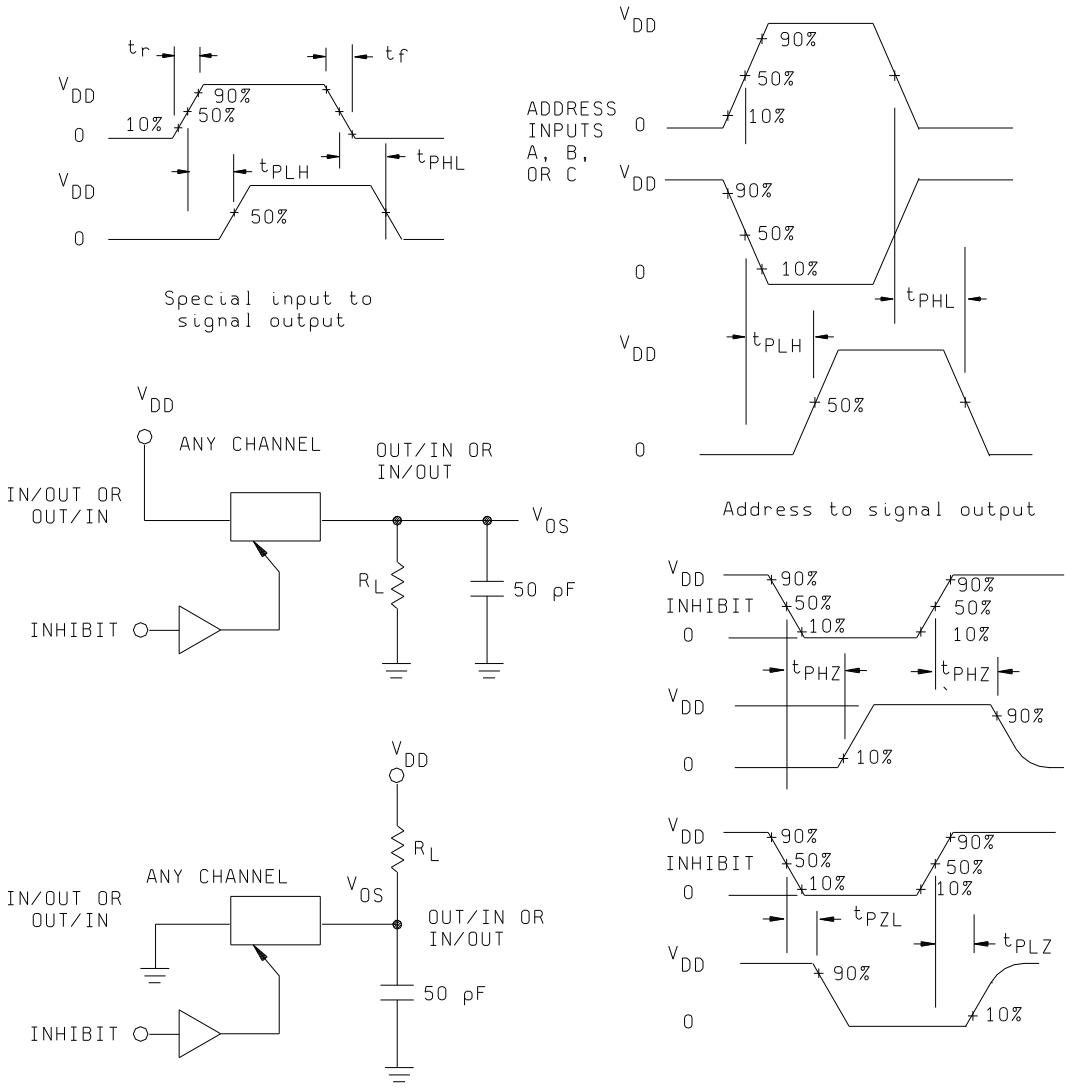


FIGURE 4. Switching waveforms and test circuits.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE **A**		**79015**
		REVISION LEVEL F	SHEET **11**

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-EC shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) T_A = +125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 4 (C_{IN} measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance. Test all applicable pins on five devices with zero failures.

d. Subgroup 7 tests shall include verification of the truth table as specified on figure 2.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,7,9
Group A test requirements (method 5005)	1,2,3,4,7,9, 10**,11**
Groups C and D end-point electrical parameters (method 5005)	1,2,3

* PDA applies to subgroup 1.
** Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).

(2) T_A = +125°C, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for original equipment manufacturer application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.

6.5 Comments. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444, or telephone (513) 296-5377.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-EC.

STANDARDIZED MILITARY DRAWING SOURCE APPROVAL BULLETIN

DATE: 94-01-13

Approved sources of supply for SMD 79015 are listed below for immediate acquisition only and shall be added to MIL-BUL-103 during the next revision. MIL-BUL-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DESC-EC. This bulletin is superseded by the next dated revision of MIL-BUL-103.

Standardized military drawing PIN	Vendor CAGE number	Vendor similar PIN 1/
7901501EX	27014	CD4052BMJ/883
7901501FX	27014	CD4052BMW/883
7901502EX	34371	CD4052BF3A
7901503EX	04713	14052B/BEAJC

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
04713	Motorola, Incorporated 5005 East McDowell Road Phoenix, AZ 85008 Point of contact: 2100 East Elliot Road Tempe, AZ 85284
27014	National Semiconductor 2900 Semiconductor Drive P.O. Box 58090 Santa Clara, CA 95052-8090 Point of contact: 333 Western Avenue South Portland, ME 04106
34371	Harris Semiconductor P.O. Box 883 Melbourne, FL 32902-0883